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Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

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•			Application Number	09/939,149	211-2
INF	ORMATION DIS	SCLOSURE	Filing Date	08/24/2001	73
STA	ATEMENT BY A	APPLICANT	First Named Inventor	Paul Mansky	TED 0 4 2000 12
017	TIEMENT D		Group Art Unit	1754 2850	
	(use as many sheets as	s necessary)	Examiner Name	David W	agins &
Sheet	1 of 0		Attorney Docket Number	1012-119(200	1 SET LE TRANS

Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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Examiner Signature	David	Wisains	Date Considered	02/04/2003

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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INF	ORMATION		DISCLOSURE	Filing Date	08/24/2001			
STA	TEMENT	BY	APPLICANT	First Named Inventor	Paul Mansky			
• · · ·			/	Group Art Unit	1754 2856	3 2000 4		
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neet	1	of	0	Attorney Docket Number	1012-119(2001	-OZ ADFMARY OF		

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INFORMATION DISCLOSURE	Filing Date	08/24/2001/	2				
STATEMENT BY APPLICANT [First Named Inventor	Paul Mansky	अवा ही				

Group Art Unit

Examiner Name

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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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	INFORMATION DISCLOSURE	Filing Date	08/24/2001 SER 0 1 BOOK 5/
	STATEMENT BY APPLICANT	First Named Inventor	Paul Mansky
ı		Group Art Unit	1754 1 656A
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Attorney Docket Number

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 3 of 3

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Application Number	09/939,149	OLE
Filing Date	08/24/2001	Ē/
First Named Inventor	Paul Mansky	FER O. W
Group Art Unit	17542856	2002
Examiner Name	David W	Mains &
Attorney Docket Number	1012-119(200	

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Examiner Initials	Cite No.1	U.S. Patent I Number	Cocument Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Where	Relevant or Relevant Appear	
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Sheet 1 of 1

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Application Number	09/939,149	7
Filing Date	08/24/2001	
First Named Inventor	Paul Manksy 🔪 🕜	
Group Art Unit	1754-28560	
Examiner Name	David Wagins	52.
Attorney Docket Number	1012-119(2001-021)	<i>"\07</i>

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 1 of 1

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Application Number	09/939,149	*
Filing Date	08/24/2001	Ur.
First Named Inventor	Paul Manky	```,
Group Art Unit	17542856	
Examiner Name	David Wid	albs 50/
Attorney Docket Numbe		21/20

			U.S. PATENT DOCU	MENTS		
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First Named Inventor	Paul Manksy	> ~.
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Examiner Name	David W	IDAMAS
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